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**SUPPLEMENTAL INFORMATION
DISCLOSURE STATEMENT BY
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Complete if Known	
Application Number	10/754,002
Filing Date	01/08/2004
First Named Inventor	Daniel E. Resasco et al.
Group Art Unit	1754 (Conf. No. 6016)
Examiner Name	S. Hendrickson
Attorney Docket Number	5820.645

U. S. PATENT DOCUMENTS						
EXAM INIT.	Cite No. 1	U.S. PATENT NUMBER Number	Kind Code ² (If known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD- YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
SLP		5424054		Bethune	06/13/1995	
		5500200		Mandeville et al.	03/19/1996	
		5747161		Iijima	05/05/1998	
		6221330		Moy et al.	04/24/2001	
		6312303		Yaniv et al.	11/06/2001	
		6346189		Dai et al.	02/12/2002	
		6401526		Dai et al.	06/11/2002	
		6426134		Lavin et al.	07/30/2002	
		6432866		Tennent et al.	08/13/2002	
		6479939		Yaniv et al.	11/12/2002	
		6573643		Kumar et al.	06/03/2003	
		6580225		Yaniv et al.	06/17/2003	
		6596187		Coll et al.	07/22/2003	
		6664722		Yaniv et al.	12/16/2003	
		6656339		Talin et al.	12/02/2003	
✓		6599961		Pienkowski et al.	07/29/2003	



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SLA		6699457		Cortright et al.	03/02/2004	
SLA		6761870		Smalley et al.	07/13/2004	
SLA		60/101093		Smalley et al.	09/18/1998	
SLP		US2003/0077515A1		Chen et al.	04/24/2003	
SLA		US2003/0089893A1		Niu et al.	05/15/2003	
SLA		US2003/0147802A1		Smalley et al.	08/07/2003	
SLA		US2003/0175200A1		Smalley et al.	09/18/2003	
SLA		US2003/0180526A1		Winey et al.	09/25/2003	
SLA		US2004/0009346A1		Jang et al.	01/15/2004	
SLA		US2004/0028859A1		LeGrande et al.	02/12/2004	

FOREIGN PATENT DOCUMENTS

EXAM INIT.	Cite No. 1	Foreign Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM- DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T*
		Office 3	Number 4	Kind Codes (if known)			
SLD			PCT/US03/19664		International Search Report	03/31/2004	
SLA			WO 03/048038		PCT/US	06/12/2003	
SLA			WO 04/001107		PCT/US	12/31/2003	
SLA			EP 01 93 9821		European Search Report	06/09/2004	
SLA			EP 0 945 402 A1		SHIMADZU CORP; Res. Inst. Innovative Tech. Earch	09/29/1999	

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SLA		CHATTOPADHYAY, et al., "A Route for Bulk Separation of Semiconducting from Metallic Singel-Wall Carbon Nanotubes", Journal of American Chemical Society, Vol. 125, No. 11, pp. 3370-3375, 2003.
SLA		CHEN et al., "Bulk Separative Enrichment in Metallic or Semiconducting Single-Walled Carbon Nanotubes", Nano Letters, xxxx Vol. 0, No. 0, page est: 4.9 A-E.
SLA		Patent Abstracts of Japan, Vol. 1996, no. 12, December 26, 1996, and JP 0 8 198611 A (NEC CORP), Aug. 6, 1996, Abstract.
SLA		^{TOHJI} TAHJI et al., "Purification Procedure for Single-Wall Nanotubes", J. Phys. Chem. B, Vol. 101, pp. 1974-1978 (1997).
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